

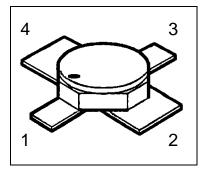


HiRel NPN Silicon RF Transistor

BFY183(ES)

Features

- For low noise, high-gain broadband amplifiers at collector currents from 2 mA to 30 mA
- Hermetically sealed microwave package
- f_T= 8GHz F = 2.3 dB at 2 GHz



Product validation

• CSA Space Qualified ESCC Detail Spec. No.: 5611/006 Type Variant No. 05

Description

ESD: **E**lectro**s**tatic **d**ischarge sensitive device, observe handling precautions!

Table 1Product information

Туре	Comment	Pin Conf		Package		
		1	2	3	4	
BFY183(ES)	For flight use	6	F			Micro-X1
BFY183(P) ¹	Not for flight use ¹		E	В		

¹ (P) parts have the same fit, form and function as (ES) parts, no screening acc. to Chart F3 in ESCC Generic Specification No. 5010



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1 Maximum ratings

Table 2Maximum ratings

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Тур.	Max.		
Collector-emitter voltage	V _{CEO}	-	-	12	V	
Collector-emitter voltage	V _{CES}	-	-	20	V	V _{BE} =0
Collector-base voltage	V _{сво}	-	-	20	V	
Emitter-base voltage	V _{EBO}	-	-	2	V	
Collector current	/ _c	-	-	65	mA	
Base current ¹	/ _B	-	-	5	mA	
Total power dissipation ²	P _{tot}	-	-	450	mW	<i>T</i> _s ≤ 99 °C
Junction temperature	Tj	-	-	200	°C	
Operating temperature	T _{op}	-65	-	200	°C	
Storage temperature	T _{stg}	-65	-	200	°C	

 $^{^{1}}$ The maximum permissible base current for V_{FBE} measurements is 20mA (spot-measurement duration < 1s)

² For T_S > 99 °C derating is required. T_S is measured on the collector lead at the soldering point to the PCB



Thermal characteristics

Thermal characteristics 2

Thermal characteristics Table 3

Parameter	Symbol	Values			Unit	Note / Test Condition	
		Min.	Тур.	Max.			
Thermal resistance, junction –soldering point	<i>R</i> _{th,JS}	-	-	225	K/W	<i>T</i> _s is measured on the collector lead at the soldering point to the PCB	
Soldering Temperature	T _{sol}	-	-	250	°C	Duration 5 seconds maximum at a distance of not less than 0.5mm from the device body and the same lead shall not be resoldered until 3 minutes have elapsed.	

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Electrical characteristics

Electrical characteristics 3

at T_A=25°C, unless otherwise specified

Static characteristics Table 4

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Тур.	Max.		
Collector-base cutoff current	I _{сво}	-	-	100	μA	$V_{\rm CB} = 20V, I_{\rm E} = 0A$
Collector-emitter cutoff current ¹	I _{CEX}	-	-	300	μΑ	$V_{CE} = 12V, I_{B} = 0.3 \mu A$
Collector-base cutoff current	I _{CBO}	-	-	50	nA	$V_{\rm CB} = 10 V, I_{\rm E} = 0 A$
Emitter base cuttoff current	I _{EBO}	-	-	25	μA	$V_{\rm EB} = 2V, I_{\rm C} = 0A$
Emitter base cuttoff current	I _{EBO}	-	-	0.5	μA	$V_{\rm EB} = 1$ V, $I_{\rm C} = 0$ A
Base-Emitter forward voltage	V _{FBE}	-	-	1	V	$I_{\rm E}$ = 30mA, $I_{\rm C}$ = 0A
DC current gain	h _{FE}	55	90	160	-	$I_{\rm C} = 5 {\rm mA}, V_{\rm CE} = 8 {\rm V}$

Table 5 **Dynamic characteristics**

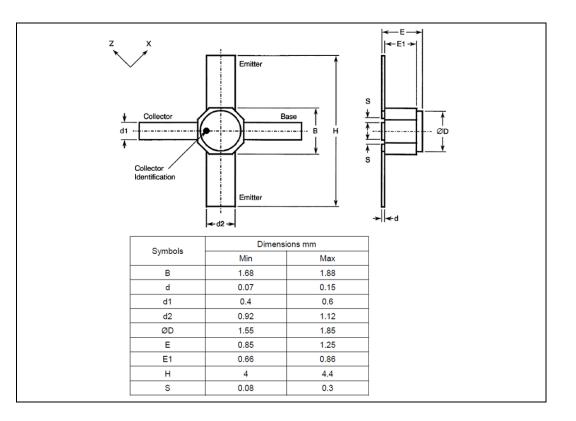
Parameter	Symbol	Values			Unit	Note / Test Condition	
		Min.	Тур.	Max.			
Transition frequency	f _T	6.5 -	7.5 8	-	GHz	/ _c = 20mA, V _{cε} = 5V, <i>f</i> = 500MHz / _c = 25mA, V _{cε} = 8V, <i>f</i> = 500MHz	
Collector-base capacitance	Ссв	-	0.32	0.44	рF	<i>V</i> _{CB} = 10V, <i>V</i> _{BE} = vbe= 0, f= 1MHz	
Collector-emitter capacitance	CCE	-	0.34	-	рF	<i>V</i> _{CE} = 10V, <i>V</i> _{BE} = vbe= 0, f= 1MHz	
Emitter-base capacitance	СЕВ	-	1.1	1.4	pF	<i>V</i> _{EB} =0.5V, <i>V</i> _{CB} = vcb= 0, f= 1MHz	
Noise Figure	F	-	2.3	2.9	dB	I_{c} = 8mA, V_{ce} = 5V, f = 2GHz, Z_{s} = Z_{sopt}	
Power Gain ²	G _{ma}	12.5	14	-	dB	I_{c} = 20mA, V_{ce} = 5V, f = 2GHz, Z_{s} = Z_{sopt} , Z_{L} = Z_{Lopt}	
Transducer gain	S _{21e} ²	9	10.5	-	dB	I_{c} = 20mA, V_{ce} = 5V, f = 2GHz, $Z_{s} = Z_{L} = 50\Omega$	
Output power	Pout	13.5	14.5	-	dBm	$I_{\rm C}$ = 30mA, $V_{\rm CE}$ = 5V, f = 2GHz, $P_{\rm IN}$ = 7dBm, $Z_{\rm S}$ = $Z_{\rm L}$ = 50 Ω	

$$^{2}G_{ma} = \left|\frac{S21}{S12}\right| (k - \sqrt{k^{2} - 1}), G_{ms} = \left|\frac{S21}{S12}\right|$$

¹ This test assures $V_{(BR)CE0} > 12V$



4 Package outlines



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